

# Jinghao Zhao

## List of Publications by Year in descending order

Source: <https://exaly.com/author-pdf/2218160/publications.pdf>

Version: 2024-02-01

7  
papers

20  
citations

2258059

3  
h-index

2053705

5  
g-index

7  
all docs

7  
docs citations

7  
times ranked

18  
citing authors

#	ARTICLE	IF	CITATIONS
1	Displacement Damage Effects in Backside Illuminated CMOS Image Sensors. IEEE Transactions on Electron Devices, 2022, 69, 2907-2914.	3.0	2
2	Impact of heavy-ion irradiation on gate oxide reliability of silicon carbide power MOSFET. Radiation Effects and Defects in Solids, 2021, 176, 1038-1048.	1.2	3
3	Study of the influence of gamma irradiation on long-term reliability of SiC MOSFET. Radiation Effects and Defects in Solids, 2020, 175, 559-566.	1.2	7
4	Comprehensive study on hot carrier reliability of radiation hardened H-gate PD SOI NMOSFET after gamma radiation. Radiation Effects and Defects in Solids, 2019, 174, 606-616.	1.2	1
5	A study on effects of total ionizing dose on hot carrier effect of PD I/O SOI PMOSFETs. Results in Physics, 2019, 13, 102223.	4.1	1
6	Hot carrier reliability of radiation hardened T-gate PD SOI NMOSFET after TID radiation. , 2019, , .		0
7	Read Static Noise Margin Decrease of 65-nm 6-T SRAM Cell Induced by Total Ionizing Dose. IEEE Transactions on Nuclear Science, 2018, 65, 691-697.	2.0	6